



octoScope Demonstrates New Smartphone Test Platform

President Fanny Mlinarsky Speaks on OTA Test Methods and Metrics at NIWeek

MARLBORO, MA — July 26, 2011 — octoScope, Inc. a RF and wireless company, will attend NIWeek, National Instruments 17th annual technology conference, and demonstrate a new platform for smartphone testing in National Instruments RF Pavilion. octoScope president Fanny Mlinarsky will also speak on Over-The-Air (OTA) test methods and metrics.

When/Where

- **Demonstration**

Tuesday-Thursday, August 2 to 4, 2011
National Instruments RF Pavilion

- **TS5101 Over-the-Air Test Methods and Metrics Technical Session**

10:30-11:30 a.m. Wednesday, August 3, 2011

Modern smart phones with cellular, 3G/4G, Wi-Fi, Bluetooth and GPS radios cry out for OTA test methods due to their sheer number of connections. This session will review OTA test methods and metrics being developed for 3GPP and CTIA and discuss practical approaches to fast and accurate OTA-based production testing.

Austin Convention Center
Austin, TX

For More Information

For more information about octoScope or to schedule an appointment and demonstration, please visit www.octoscope.com or contact sales@octoscope.com. Please visit www.ni.com/niweek to register for NIWeek.

About OctoScope

OctoScope offers RF and wireless technology consulting services, third-party product development and wireless test solutions for qualifying modern communications networks, including LTE and Wi-Fi.

For more information, please visit www.octoscope.com or contact info@octoscope.com.